AFP tracker production and testing

I. López Paz for the AFP group

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The AFP Tracker Module

Requirements

- Radiation hardness
- Slim-edge for acceptance
- Position resolution for pT and t reconstruction resolution

Chip: FE-I4 chip

- Radiation hard electronics: 250 Mrad
- 50x250 µm² pixels
 - + Charge collection information (4-bit ToT)
 - + Maximum charge sharing in X (along 50 µm pitch)
- FE-I4 signal (HitOr) as trigger in initial one-arm phase

Sensor: 3D Silicon sensor

- Column-like electrodes -> Radiation hard
 - Fluence: $>5x10^{15} n_{eq}/cm^2$
- Slim-edged down to ~180 μm
- 2nd use of 3D technology in HEP (1st IBL)





AFP Tracker Module Production



Sensor Production (I)

CNM 3D Silicon sensor

- First CNM production (January 2015) for AFP had low yield:
 - 40 sensors produced in total (5 wafers)
 - 5 broken sensors
 - 19 bad quality IV: $V_{BD} < 10 \text{ V}$
 - 7 medium quality IV: 10 V < V_{BD} < 20 V
 - 9 good quality IV: $V_{BD} > 20 V$
- Second production soon to be finished (~1 month)

Sensor qualification (at CNM)

- 3D Guard-Ring IV measurement:
 - Proven not to be reliable, probes a small fraction of total pixels
- Under Bump Metallization (UBM) contact
 - Contact UBM in chuck, more reliable than 3D G-R
- For 2nd production will use temporary metallization for sensor qualification



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Sensor Production (II)

Slim-edge measurement

- Edge slimming at CNM: standard diamond saw
- Check edge extension after slim-edge
- Irradiation campaign

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- Try to recover bad quality IV sensors
- Irradiate sensors at Ljubljana with neutrons up to moderate fluences (10¹⁴ n_{eq}/cm²)
 - Low dose thought to improve inter-pixel isolation (p-stop)
- Recovered 5 sensors out of 11
 - 4 Good quality
 - 1 already installed in Far Station
 - 1 Medium quality





IV of 6682-w11-s6 for different irradiations



Bare Assembly and Tracker Module Production

- Bare Assembly: Sensor flip-chipped to FE-I4 chip
- Select sensor based on IV behavior at "wafer" level to be flip-chipped
- Flip-chip done "in-house" at IFAE
- Tracker Module: Bare Assembly + carrier card + Flex (at IFAE)
- Bare Assembly is glued onto the carrier card with alignment marks
- Flex also glued onto carrier card
- Chip is wire-bonded to Flex



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Carrier card



Flex



Pick and Place machine



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Wire-bond machine



BARE IVs

6682-W05-S01





Tracker Module Testing

- Alignment measurement with X-ray microscope
- Module testing
 - First calibration measurements performed
 - Tuning of device to standard values
 - Threshold: 2000 e; ToT: 10 ToT at 20 ke
 - Source scan (Sr90)
 - Look for disconnected pixels
 - Modules are sent to CERN



Within ~100 µm due to not optimal alignment marks (to be improved)



Tracker Module Quality Assurance



Full Readout Chain Testing

- Full readout chain tested before/after installation:
 - Tracker module/s
 - Local Trigger Board (LTB)
 - Routes Low and High Voltage, I/O and clock to the modules
 - Gets the HitOr signal from the modules and sends a trigger signal via HitBus chip

Optoboard

- Intermediate stage between LTB and DAQ (HSIO)
- Gets/Sends I/O/clock from HSIO via optical fibre
- Sends/Gets I/O/clock to LTB via electrical cable
- High Speed Input/Output (HSIO)
- Calibrates modules/Runs data acquisition











Status after early installation

- A total of 11 tracker modules were produced
 - 1 broken due to wire-bond short
 - 2 non-responsive chips
 - 1 module with wide area of disconnected pixels
 - 7 Medium-Good quality modules -> Installed
 - 3 in Near Station
 - 4 in Far Station



- Inside the pot, so not accessible until TS1 (June)
- Use plane without HV, but 3D detectors are still functional with no bias
- Worst modules can be replaced in short accesses
- Read-out of trackers functional after installation









